







CD54HC4002, CD74HC4002

ZHCSPY3F - AUGUST 1997 - REVISED FEBRUARY 2022

CDx4HC4002 高速 CMOS 逻辑双路 4 输入或非门

1 特性

 V_{CC} = 5V, C_L = 15pF 且 T_A = 25℃ 时的传播延迟典型值为

扇出(超出温度范围)

- 标准输出:10 个 LSTTL 负载

- 总线驱动器输出:15 个 LSTTL 负载

• 宽工作温度范围:-55℃ 至 125℃

• 平衡的传播延迟及转换时间

• 与 LSTTL 逻辑 IC 相比,功耗显著降低

HC 类型

- 2V至6V范围内运行

- 高抗噪性: 当 V_{CC} = 5 V 时, N_{IL} = 30%, N_{IH} = V_{CC} 的 30%

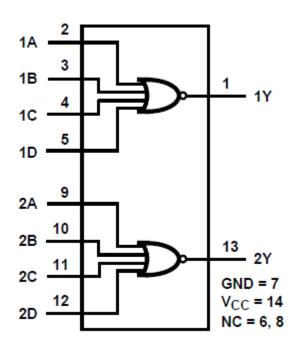
2 说明

HC4002 逻辑门利用硅栅 CMOS 技术,在标准 CMOS 集成电路的低功耗下实现与 LSTTL 电路各门接近的运 行速度。所有器件都能够驱动 10 LSTTL 负载。 HC4002 系列逻辑器件功能齐全,并与标准 LS 系列逻 辑器件引脚兼容。

器件信息

零件编号	封装 ⁽¹⁾	封装尺寸 (标称值)			
CD74HC4002M	SOIC (14)	8.65 mm × 3.9 mm			
CD54HC4002F3A	CDIP (14)	19.55 mm × 6.71 mm			
CD74HC4002E	PDIP (14)	19.31mm × 6.35mm			
CD74HC4002PW	TSSOP (14)	5.0mm × 4.4mm			

如需了解所有可用封装,请参阅数据表末尾的可订购产品附 (1)



功能方框图



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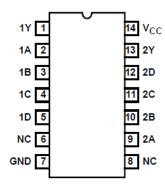
3 Revision History

注:以前版本的页码可能与当前版本的页码不同

C	Changes from Revision E (October 2003	3) to Revision F	F (February 2022)	Page
•	更新了整个文档中的编号、	格式、表格、	图和交叉参考	. 以反映现代数据表标准	1



4 Pin Configuration and Functions



J, N, D, or PW package 14-Pin CDIP, PDIP, SOIC, or TSSOP Top View



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

			MIN	MAX	UNIT
V _{CC}	Supply voltage		- 0.5	7	V
I _{IK}	Input diode current	For V _I < -0.5 V or V _I > V _{CC} + 0.5 V		± 20	mA
I _{OK}	Output diode current	For $V_O < -0.5 \text{ V}$ or $V_O > V_{CC} + 0.5 \text{ V}$		± 20	mA
I _O	Output source or sink current per output pin	For $V_O > -0.5 \text{ V}$ or $V_O < V_{CC} + 0.5 \text{ V}$		± 25	mA
	Continuous current V _{CC} or ground cu	urrent		± 50	mA
TJ	Junction temperature			150	
T _{stg}	Storage temperature range	- 65	150		
	Lead temperature (Soldering 10s) (S	OIC - lead tips only)		300	

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 Recommended Operating Conditions

			MIN	MAX	UNIT
V	Supply voltage range	HC Types	2	6	V
V _{CC}	Supply voltage range	HCT Types	4.5	5.5	V
V _I , V _O	Input or output voltage	·	0	V _{CC}	V
		2 V		1000	ns
t _t	Input rise and fall time	4.5 V		500	ns
		6 V		400	ns
T _A	Temperature range		- 55	125	$^{\circ}\!\mathbb{C}$

5.3 Thermal Information

		D (SOIC)	N (PDIP)	NS (SO)	PW (TSSOP)	
THERMAL METRIC		14 PINS	14 PINS	14 PINS	14 PINS	UNIT
R ₀ JA	Junction-to-ambient thermal resistance ⁽¹⁾	86	80	76	113	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

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5.4 Electrical Characteristics

	PARAMETER	TEST	Vcc	:	25 o C		-40℃ to	85℃	-55℃ to 125℃		UNIT
	PARAMETER	CONDITIONS ⁽¹⁾	(V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONIT
			2	1.5			1.5		1.5		V
V _{IH}	High level input voltage		4.5	3.15			3.15		3.15		V
	9		6	4.2			4.2		4.2		V
			2			0.5		0.5		0.5	V
V _{IL}	Low level input voltage		4.5			1.35		1.35		1.35	V
	, sinage		6			1.8		1.8		1.8	V
	High level output voltage	I _{OH} = - 20 μA	2	1.9			1.9		1.9		V
		I _{OH} = - 20 μA	4.5	4.4			4.4		4.4		V
V _{OH}		I _{OH} = - 20 μA	6	5.9			5.9		5.9		V
	High level output	I _{OH} = - 4 mA	4.5	3.98			3.84		3.7		V
	voltage	I _{OH} = - 5.2 mA	6	5.48			5.34		5.2		V
	1 1 4 4	I _{OL} = 20 μA	2			0.1		0.1		0.1	V
	Low level output voltage	I _{OL} = 20 μA	4.5			0.1		0.1		0.1	V
V _{OL}	voltage	I _{OL} = 20 μA	6			0.1		0.1		0.1	V
	Low level output	I _{OL} = 4 mA	4.5			0.26		0.33		0.4	V
	voltage	I _{OL} = 5.2 mA	6			0.26		0.33		0.4	V
I _I	Input leakage current	V _I = V _{CC} or GND	6			±0.1		±1		±1	μА
I _{CC}	Supply current	$V_I = V_{CC}$ or GND	6			2		20		40	μА

⁽¹⁾ $V_I = V_{IH}$ or V_{IL} , unless otherwise noted.

5.5 Switching Characteristics

Input t_r , $t_f = 6$ ns

	PARAMETER	TEST CONDITIONS	V _{CC} (V)	25℃	-40℃ to 85℃	-55℃ to 125℃	UNIT	
		CONDITIONS		TYP MAX	MAX	MAX		
HC TYPES								
			2	100	125	150	ns	
t _{PLH} , t _{PHL}	Propagation delay, nA, nB, nC, nD to nY	C _L = 50 pF	4.5	20	25	30	ns	
			6	17	21	26	ns	
		C _L = 15 pF	5	8			ns	
			2	75	95	110	ns	
t _{TLH} , t _{THL}	Output transition times (see Figure 1)	C _L = 50 pF	4.5	15	19	22	ns	
	i igaio i)		6	13	16	19	ns	
C _{IN}	Input capacitance			10	10	10	pF	
C _{PD}	Power dissipation capacitance ⁽¹⁾ (2)	C _L = 15 pF	5	22			pF	

⁽¹⁾ C_{PD} is used to determine the dynamic power consumption, per gate. (2) $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ where f_i = input frequency, C_L = output load capacitance, V_{CC} = supply voltage.



6 Parameter Measurement Information

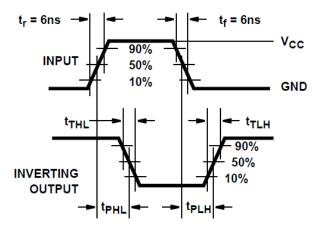


图 6-1. HC and HCU Transition Times and Propagation Delay Times, Combination Logic

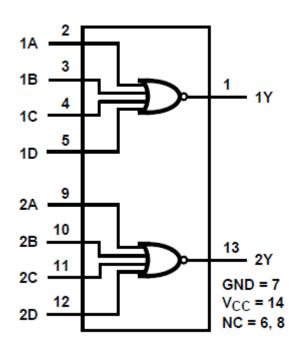


7 Detailed Description

7.1 Overview

The 'HC4002 logic gate utilizes silicon gate CMOS technology to achieve operating speeds similar to LSTTL gates with the low power consumption of standard CMOS integrated circuits. All devices have the ability to drive 10 LSTTL loads. The 'HC4002 logic family is functional as well as pin compatible with the standard LS logic family.

7.2 Functional Block Diagram



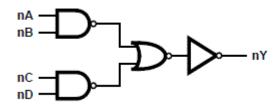


图 7-2. Logic Symbol

图 7-1. Functional Diagram

7.3 Device Functional Modes

表 7-1. Truth Table⁽¹⁾

	INPUTS									
nA	nB	nC	nD	nY						
L	L	L	L	Н						
Н	Х	Х	Х	L						
Х	Н	Х	Х	L						
Х	Х	Н	Х	L						
Х	Х	Х	Н	L						

(1) H = High Voltage Level, L = Low Voltage Level, X = Irrelevant

8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

9 Layout

9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

10.1 接收文档更新通知

要接收文档更新通知,请导航至 ti.com 上的器件产品文件夹。点击*订阅更新* 进行注册,即可每周接收产品信息更改摘要。有关更改的详细信息,请查看任何已修订文档中包含的修订历史记录。

10.2 支持资源

TI E2E™ 支持论坛是工程师的重要参考资料,可直接从专家获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题可获得所需的快速设计帮助。

链接的内容由各个贡献者"按原样"提供。这些内容并不构成 TI 技术规范,并且不一定反映 TI 的观点;请参阅 TI 的《使用条款》。

10.3 Trademarks

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10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 术语表

TI 术语表

本术语表列出并解释了术语、首字母缩略词和定义。

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
	()	()			(-)	(4)	(5)		(-/
CD54HC4002F3A	Active	Production	CDIP (J) 14	25 TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8404401CA CD54HC4002F3A
CD54HC4002F3A.A	Active	Production	CDIP (J) 14	25 TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8404401CA CD54HC4002F3A
CD74HC4002E	Active	Production	PDIP (N) 14	25 TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74HC4002E
CD74HC4002E.A	Active	Production	PDIP (N) 14	25 TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74HC4002E
CD74HC4002M	Obsolete	Production	SOIC (D) 14	-	-	Call TI	Call TI	-55 to 125	HC4002M
CD74HC4002M96	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU SN NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4002M
CD74HC4002M96.A	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4002M
CD74HC4002MT	Obsolete	Production	SOIC (D) 14	-	-	Call TI	Call TI	-55 to 125	HC4002M
CD74HC4002PWR	Active	Production	TSSOP (PW) 14	2000 LARGE T&R	Yes	NIPDAU SN	Level-1-260C-UNLIM	-55 to 125	HJ4002
CD74HC4002PWR.A	Active	Production	TSSOP (PW) 14	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HJ4002
CD74HC4002PWRG4	Active	Production	TSSOP (PW) 14	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HJ4002

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

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OTHER QUALIFIED VERSIONS OF CD54HC4002, CD74HC4002:

Catalog : CD74HC4002

Military: CD54HC4002

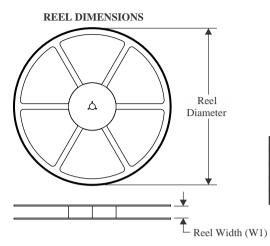
NOTE: Qualified Version Definitions:

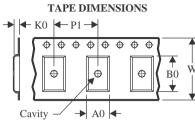
- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

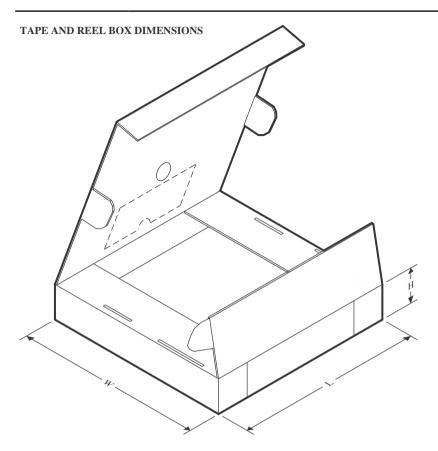


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC4002M96	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CD74HC4002PWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD74HC4002PWR	TSSOP	PW	14	2000	330.0	12.4	6.85	5.45	1.6	8.0	12.0	Q1
CD74HC4002PWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD74HC4002PWRG4	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD74HC4002PWRG4	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1



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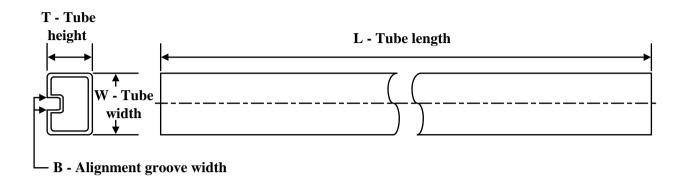
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC4002M96	SOIC	D	14	2500	353.0	353.0	32.0
CD74HC4002PWR	TSSOP	PW	14	2000	353.0	353.0	32.0
CD74HC4002PWR	TSSOP	PW	14	2000	366.0	364.0	50.0
CD74HC4002PWR	TSSOP	PW	14	2000	353.0	353.0	32.0
CD74HC4002PWRG4	TSSOP	PW	14	2000	356.0	356.0	35.0
CD74HC4002PWRG4	TSSOP	PW	14	2000	353.0	353.0	32.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CD74HC4002E	N	PDIP	14	25	506	13.97	11230	4.32
CD74HC4002E	N	PDIP	14	25	506	13.97	11230	4.32
CD74HC4002E.A	N	PDIP	14	25	506	13.97	11230	4.32
CD74HC4002E.A	N	PDIP	14	25	506	13.97	11230	4.32



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



CERAMIC DUAL IN LINE PACKAGE



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4040083-5/G





CERAMIC DUAL IN LINE PACKAGE



NOTES:

- 1. All controlling linear dimensions are in inches. Dimensions in brackets are in millimeters. Any dimension in brackets or parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This package is hermitically sealed with a ceramic lid using glass frit.
- His package is remitted by sealed with a ceramic its using glass mit.
 Index point is provided on cap for terminal identification only and on press ceramic glass frit seal only.
 Falls within MIL-STD-1835 and GDIP1-T14.



CERAMIC DUAL IN LINE PACKAGE



N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.





SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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